







THVD2412, THVD2442 SLLSFR1A - NOVEMBER 2023 - REVISED MARCH 2024

THVD24x2 ±70V Fault-Protected 3V to 5.5V Full Duplex RS-485 Transceivers With IEC ESD

1 Features

Texas

INSTRUMENTS

- Meets or exceeds the requirements of the TIA/ EIA-485A and TIA/EIA-422B standards
- 3V to 5.5V supply voltage
- Differential output exceeds 2.1V for PROFIBUS compatibility with 5V supply
- Bus I/O protection
 - ±70V DC bus fault
 - ±16kV HBM ESD
 - ±8kV IEC 61000-4-2 contact discharge
 - ±8kV IEC 61000-4-2 air-gap discharge
 - ±4kV IEC 61000-4-4 fast transient burst
- Full-duplex devices available in two speed grades
 - THVD2412: 250kbps
 - THVD2442: 20Mbps
- Extended ambient temperature range: -40°C to 125°C
- Extended operational common-mode range: ±25V •
- Enhanced receiver hysteresis for noise immunity
- Low power consumption
 - Low shutdown supply current: < 10µA
 - Current during operation: < 5.6mA
- Glitch-free power-up/down for hot plug-in capability
- Open, short, and idle bus failsafe •
- Thermal shutdown
- 1/8 unit load (up to 256 bus nodes) in 7V to 12V ٠ common mode range
- Small 3mm x 3mm VSON package to save board • space

2 Applications

- Motor drives •
- Factory automation and control
- **HVAC** systems
- **Building automation** ٠
- Grid infrastructure
- Electricity meters ٠
- **Process analytics**
- Video surveillance

3 Description

THVD2412 and THVD2442 are ±70V fault-protected, full-duplex, RS-422/RS-485 transceivers operating on a single 3V to 5.5V supply. Bus interface pins are protected against overvoltage conditions during all modes of operation ensuring robust communication in rugged industrial environments.

These devices feature integrated IEC ESD protection. eliminating the need for external system-level protection components. Extended ±25V input common-mode range ensures reliable data communication over longer cable run lengths and/or in the presence of large ground loop voltages. Enhanced 250mV receiver hysteresis provides high noise rejection. In addition, the receiver fail-safe feature provides a logic high when the bus inputs are open or shorted together.

THVD24x2 devices are available in small and thermally efficient VSON packages for spaceconstrained applications. These devices are characterized over ambient temperature from -40°C to 125°C.

Package Information

PART NUMBER	PACKAGE ⁽¹⁾	PACKAGE SIZE ⁽²⁾
THVD2412 THVD2442	VSON (10)	3mm × 3mm

- For more information, see Section 11. (1)
- (2) The package size (length × width) is a nominal value and includes pins, where applicable.



THVD2412 and THVD2442 Simplified Schematic





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4 Pin Configuration and Functions





Table 4-1. Pin Functions

PIN		ТҮРЕ	DESCRIPTION	
NAME	DRC	ITFE	DESCRIPTION	
R	1	Digital output	Receive data output	
RE	2	Digital input	Receiver enable input; integrated weak pull-up (~2 MΩ)	
DE	3	Digital input	Driver enable input; integrated weak pull-down (~2 $M\Omega$)	
D	4	Digital input	Transmission data input; integrated weak pull-up (~2 MΩ)	
GND	5	Ground	Local Device ground	
Y	6	Bus output	Driver non-inverting output	
Z	7	Bus output	Driver inverting output	
В	8	Bus input	Receiver inverting bus input	
A	9	Bus input	Receiver non-inverting bus input	
V _{cc}	10	Power	3 V to 5.5 V supply voltage	
Thermal Pad	_	_	No electrical connection. Should be connected to GND plane for optimal thermal performance	



5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted) (1) (2)

		MIN	MAX	UNIT
Supply voltage	V _{CC}	-0.5	6.5	V
Bus voltage	Range at any bus pin as differential or common-mode with respect to GND	-70	70	V
Input voltage	Range at any logic pin (D, DE, or \overline{RE})	-0.3	5.7	V
Receiver output current	lo	-24	24	mA
Storage temperature	T _{stg}	-65	170	°C

(1) Operation outside the Absolute Maximum Ratings may cause permanent device damage. Absolute Maximum Ratings do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions. If used outside the Recommended Operating Conditions but within the Absolute Maximum Ratings, the device may not be fully functional, and this may affect device reliability, functionality, performance, and shorten the device lifetime.

(2) All voltage values, except differential I/O bus voltages, are with respect to ground terminal.

5.2 ESD Ratings

	Human-body model (HBM), per ANSI/ESDA/	Bus terminals and GND	±16,000	V	
V _(ESD)	Electrostatic discharge	JEDEC JS-001 ⁽¹⁾	All pins except bus terminals and GND	.,	V
		Charged-device model (CDM), per JEDEC specifi	cation JESD22-C101 ⁽²⁾	±1,500	V

(1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

(2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

5.3 ESD Ratings [IEC]

				VALUE	UNIT
V (1)	V _(ESD) ⁽¹⁾ Electrostatic discharge	Contact discharge, per IEC 61000-4-2	Bus terminals and GND	±8,000	V
V _(ESD) (1)		Air-gap discharge, per IEC 61000-4-2	Bus terminals and GND	±8,000	v
V _(EFT)	Electrical fast transient	Per IEC 61000-4-4	Bus terminals	±4,000	V

 For optimised IEC ESD performance, it is recommended to have series resistor (≥ 50 Ω) on all logic inputs to minimize transient currents going into or out of the logic pins.



5.4 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

			MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage		3		5.5	V
VI	Input voltage at any bus term	inal (separately or common mode) ⁽¹⁾	-25		25	V
V _{IH}	High-level input voltage (drive	er, driver enable, and receiver enable inputs)	2		5.5	V
V _{IL}	Low-level input voltage (drive	r, driver enable, and receiver enable inputs)	0		0.8	V
V _{ID}	Differential input voltage bus pins		-25		25	V
I _O	Output current, driver	Output current, driver			60	mA
I _{OR}	Output current, receiver	Output current, receiver			8	mA
RL	Differential load resistance		54	60		Ω
4 /4	Cignaling rate	THVD2412			250	kbps
1/t _{UI}	Signaling rate	THVD2442			20	Mbps
T _A	Operating ambient temperature		-40		125	°C
TJ	Junction temperature		-40		150	°C

(1) The algebraic convention, in which the least positive (most negative) limit is designated as minimum is used in this data sheet.

5.5 Thermal Information

		THVD2412 THVD2442	
	THERMAL METRIC ⁽¹⁾	DRC (VSON)	UNIT
		10 PINS	
R _{0JA}	Junction-to-ambient thermal resistance	46.7	°C/W
R _{0JC(top)}	Junction-to-case (top) thermal resistance	47.7	°C/W
R _{0JB}	Junction-to-board thermal resistance	19.1	°C/W
ΨJT	Junction-to-top characterization parameter	0.7	°C/W
Ψ_{JB}	Junction-to-board characterization parameter	19.1	°C/W
R _{0JC(bot)}	Junction-to-case (bottom) thermal resistance	4.6	°C/W

(1) For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

5.6 Power Dissipation

PARAMETER		TEST CONDITIONS			VALUE	UNIT
PD		Unterminated $R_L = 300 \Omega$, $C_L = 50 pF$ (driver)	THVD2412	250 kbps	258	mW
	Driver and receiver enabled, loopback		THVD2442	20 Mbps	335	
	(connect A to Y, B to Z)	RS-422 load R _L = 100 Ω, C _L = 50 pF (driver)	THVD2412	250 kbps	273	mW
	V_{CC} = 5.5 V, T _A = 125 °C, random data (PRBS7) at signaling rate		THVD2442	20 Mbps	325	
		RS-485 load	THVD2412	250 kbps	315	mW
		$R_L = 54 \Omega$, $C_L = 50 pF$ (driver)	THVD2442	20 Mbps	355	IIIVV



5.7 Electrical Characteristics

over operating free-air temperature range (unless otherwise noted). All typical values are at 25°C and supply voltage of V_{CC} = 5 V.

	PARAMETER	TI	EST CONDITIONS		MIN	TYP	MAX	UNIT
Driver								
		$R_L = 60 \Omega$, $-25 V \le V_{test} \le 25 V$	V, See Figure 6-1		1.5	2.8		V
Driver differential output		$R_L = 60 \Omega$, $-25 V \le V_{test} \le 25 V$	V, 4.5 V \le V _{CC} \le 5.5 V,	See Figure 6-1	2.1	3.3		V
V _{OD}	voltage magnitude	R _L = 100 Ω, See Figure 6-2			2	2.9		V
		R _L = 54 Ω, See Figure 6-2			1.5	2.5		V
Δ V _{OD}	Change in differential output voltage	R_L = 54 Ω or 100 Ω, See Figure	re 6-2		-50		50	mV
V _{oc}	Common-mode output voltage	R_L = 54 Ω or 100 Ω, See Figure	re 6-2		1	V _{CC} /2	3	V
$\Delta V_{OC(SS)}$	Change in steady-state common-mode output voltage	R_L = 54 Ω or 100 Ω, See Figure	re 6-2		-50		50	mV
l _{os}	Short-circuit output current	DE = V_{CC} , -70 V \leq (V _Y or V _Z):	≤ 70 V, or Y shorted to	Z	-250		250	mA
Receiver	1	1						
				V _I = 12 V		75	125	μA
			DE = 0 V, V _{CC} = 0 V	V ₁ = 25 V		200	250	μA
li –	Bus input current	DE = 0 V, V _{CC} = 0 V or 5.5 V	or 5.5 V	V ₁ = -7 V	-100	-60		μA
				V ₁ = -25 V	-350	-350		μA
V _{TH+}	Positive-going input threshold voltage ⁽¹⁾	Over common-mode range of	± 25 V		20	125	200	mV
V _{TH-}	Negative-going input threshold voltage ⁽¹⁾	Over common-mode range of	± 25 V		-200	-125	-20	mV
V _{HYS}	Input hysteresis	Over common-mode range of ± 25 V			250		mV	
V _{TH_FSH}	Input fail-safe threshold	Over common-mode range of	± 25 V		-20		20	mV
C _{A,B}	Input differential capacitance	Measured between A and B, f	= 1 MHz			50		pF
V _{OH}	Output high voltage	I _{OH} = -8 mA			V _{CC} - 0.4	V _{CC} – 0.2		V
V _{OL}	Output low voltage	I _{OL} = 8 mA				0.2	0.4	V
I _{OZ}	Output high-impedance current	$V_0 = 0 V \text{ or } V_{CC}, \overline{RE} = V_{CC}$			-1		1	μA
Logic								
I _{IN}	Input current (DE)	$3 \text{ V} \leq \text{V}_{\text{CC}} \leq 5.5 \text{ V}, 0 \text{ V} \leq \text{V}_{\text{IN}} \leq$	V _{CC}				5	μA
I _{IN}	Input current (D, RE)	$3 \text{ V} \leq \text{V}_{\text{CC}} \leq 5.5 \text{ V}, 0 \text{ V} \leq \text{V}_{\text{IN}} \leq$	V _{CC}		-5			μA
Thermal P	rotection							
T _{SHDN}	Thermal shutdown threshold	Temperature rising			150	170		°C
T _{HYS}	Thermal shutdown hysteresis				10		°C	
Supply								
UV _{VCC} (rising)	Rising under-voltage threshold on V _{CC}					2.3	2.6	V
UV _{VCC} (falling)	Falling under-voltage threshold on V _{CC}				1.95	2.2		V
UV _{VCC(hys}	Hysteresis on under-voltage of V_{CC}					150		mV



5.7 Electrical Characteristics (continued)

over operating free-air temperature range (unless otherwise noted). All typical values are at 25°C and supply voltage of V_{CC} = 5 V.

	PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	UNIT
Icc		Driver and receiver enabled	\overline{RE} = 0 V, DE = V _{CC} , No load		3.5	5.3	mA
	Supply current (quiescent),	Driver enabled, receiver disabled	$\overline{RE} = V_{CC}, DE = V_{CC},$ No load		2.5	4.2	mA
	$V_{CC} = 4.5 V \text{ to } 5.5 V$	Driver disabled, receiver enabled	$\overline{RE} = 0 V$, DE = 0 V, No load		1.8	2.4	mA
		Driver and receiver disabled	$\overline{RE} = V_{CC}$, DE = 0 V, D = open, No load		0.1	7	μΑ
		Driver and receiver enabled	\overline{RE} = 0 V, DE = V _{CC} , No load		3	4.1	mA
	Supply current (quiescent),	Driver enabled, receiver disabled	$\label{eq:RE} \begin{array}{l} \overline{RE} = V_{CC}, \ DE = V_{CC}, \\ \\ No \ load \end{array}$		2	3	mA
Icc	V_{CC} = 3 V to 3.6 V	Driver disabled, receiver enabled	$\overline{RE} = 0 V, DE = 0 V,$ No load		1.6	2.2	mA
		Driver and receiver disabled	$\overline{RE} = V_{CC}, DE = 0 V,$ D = open, No load		0.1	5	μΑ

(1) Under any specific conditions, V_{TH+} is specified to be at least V_{HYS} higher than V_{TH-} .



5.8 Switching Characteristics_250kbps

250-kbps (THVD2412) over recommended operating conditions. All typical values are at 25°C and supply voltage of V_{CC} = 5 V, unless otherwise noted.

	PARAMETER	TEST C	ONDITIONS	MIN	TYP	MAX	UNIT
Driver							
t _r , t _r Differential output rise/fall time			V _{CC} = 3 to 3.6 V, Typical at 3.3V	450	650	1200	ns
			V _{CC} = 4.5 to 5.5 V, Typical at 5 V	500	710	1200	ns
+ +	и, t _{PLH} Propagation delay	R _L = 54 Ω, C _L = 50 pF	V _{CC} = 3 to 3.6 V, Typical at 3.3V		525	750	ns
t _{PHL} , t _{PLH}	FTOpagation delay	See Figure 6-3	V_{CC} = 4.5 to 5.5 V, Typical at 5 V		560	770	ns
+	Pulso skow ittl		V _{CC} = 3 to 3.6 V, Typical at 3.3V		30	70	ns
$t_{SK(P)}$ Pulse skew, $ t_{PHL} - t_{PLH} $			V_{CC} = 4.5 to 5.5 V, Typical at 5 V		30	70	ns
t _{PHZ} , t _{PLZ}	Disable time	RE = X			33	75	ns
t _{PZH} , t _{PZL}	Enable time	RE = 0 V	See Figure 6-4		400	280	ns
		RE = V _{CC}	and Figure 6-5		2	4.5	μs
t _{SHDN}	Time to shutdown	RE = V _{CC}		50		500	ns
Receiver							
t _r , t _f	Output rise/fall time				13	20	ns
t _{PHL} , t _{PLH}	Propagation delay	C _L = 15 pF	See Figure 6-6		850	1270	ns
t _{SK(P)}	Pulse skew, t _{PHL} – t _{PLH}	-			5	45	ns
t _{PHZ} , t _{PLZ}	Disable time	DE = X	See Figure 6-7		30	40	ns
t _{PZH(1)}	E 11 /		0.5.07		90	120	ns
PZL(1)	Enable time	$DE = V_{CC}$	See Figure 6-7		900	1320	ns
^t PZH(2), ^t PZL(2)	Enable time	DE = 0 V	See Figure 6-8		3.3	5.4	μs
t _{D(OFS)}	Delay to enter fail-safe operation	0 - 15 - 5		7	11	18	μs
t _{D(FSO)}	Delay to exit fail-safe operation	- C _L = 15 pF	See Figure 6-9	540	850	1260	ns
t _{SHDN}	Time to shutdown	DE = 0 V	See Figure 6-8	50		500	ns

5.9 Switching Characteristics_20Mbps

20-Mbps (THVD2442) over recommended operating conditions. All typical values are at 25°C and supply voltage of V_{CC} = 5 V, unless otherwise noted

	PARAMETER	TEST C	MIN	TYP	MAX	UNIT				
Driver										
			V _{CC} = 3 to 3.6 V, Typical at 3.3 V	4	8	15	ns			
t _r , t _f	Differential output rise/fall time		V_{CC} = 4.5 to 5.5 V, Typical at 5 V	4	7	15	ns			
		R _L = 54 Ω, C _L = 50 pF	V _{CC} = 3 to 3.6 V, Typical at 3.3 V	6	15	30	ns			
t _{PHL} , t _{PLH}	Propagation delay	See Figure 6-3	V_{CC} = 4.5 to 5.5 V, Typical at 5 V	6	13	26	ns			
•	Bulaa akaw Itaat I		V _{CC} = 3 to 3.6 V, Typical at 3.3 V		1	3	ns			
t _{SK(P)}	Pulse skew, t _{PHL} – t _{PLH}		V_{CC} = 4.5 to 5.5 V, Typical at 5 V		1	3	ns			
t _{PHZ} , t _{PLZ}	Disable time	RE = X			15	35	ns			
t _{PZH} , t _{PZL} Enable time	En able time	RE = 0 V	See Figure 6-4		8	39	ns			
	Enable time	RE = V _{CC}	and Figure 6-5		2	4.5	μs			
t _{SHDN}	Time to shutdown	RE = V _{CC}		50		500	ns			



5.9 Switching Characteristics_20Mbps (continued)

20-Mbps (THVD2442) over recommended operating conditions. All typical values are at 25°C and supply voltage of V_{CC} = 5 V, unless otherwise noted

	PARAMETER	TEST CO	NDITIONS	MIN	TYP	MAX	UNIT
Receiver							
t _r , t _f	Output rise/fall time				1.5	6	ns
t _{PHL} , t _{PLH}	Propagation delay	C _L = 15 pF	See Figure 6-6		40	57	ns
t _{SK(P)}	Pulse skew, t _{PHL} – t _{PLH}					5	ns
t _{PHZ} , t _{PLZ}	Disable time	DE = X	See Figure 6-7		11	25	ns
t _{PZH(1)} , t _{PZL(1)}	Enable time	DE = V _{CC}	See Figure 6-7		55	82	ns
t _{PZH(2)} , t _{PZL(2)}	Enable time	DE = 0 V	See Figure 6-8		1.5	4.5	μs
t _{D(OFS)}	Delay to enter fail-safe operation	- C ₁ = 15 pF	See Figure 6-9	7	11	18	μs
t _{D(FSO)}	Delay to exit fail-safe operation	10L - 13 pr	See Figure 0-9	22	25	50	ns
t _{SHDN}	Time to shutdown	DE = 0 V	See Figure 6-8	50		500	ns



5.10 Typical Characteristics





5.10 Typical Characteristics (continued)



6 Parameter Measurement Information



Figure 6-1. Measurement of Driver Differential Output Voltage With Common-Mode Load



Figure 6-2. Measurement of Driver Differential and Common-Mode Output With RS-485 Load



Figure 6-3. Measurement of Driver Differential Output Rise and Fall Times and Propagation Delays



Figure 6-4. Measurement of Driver Enable and Disable Times With Active High Output and Pull-Down Load



Figure 6-5. Measurement of Driver Enable and Disable Times With Active Low Output and Pull-up Load





Figure 6-6. Measurement of Receiver Output Rise and Fall Times and Propagation Delays



Figure 6-7. Measurement of Receiver Enable/Disable Times With Driver Enabled



Figure 6-8. Measurement of Receiver Enable Times With Driver Disabled



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Figure 6-9. Measurement of Fail-Safe Delay



7 Detailed Description

7.1 Overview

THVD2412 and THVD2442 are fault-protected, full-duplex RS-485/RS-422 transceivers available in 10-VSON package. THVD2412 allows for data transmission up to 250kbps, while THVD2442 is suitable for data transmission up to 20Mbps. The devices have active-high driver enable and active-low receiver enable. A shutdown current of less than 10µA can be achieved by disabling both driver and receiver.

7.2 Functional Block Diagrams



Figure 7-1. THVD24x2 Block Diagram

7.3 Feature Description

7.3.1 ±70-V Fault Protection

THVD24x2 transceivers have extended bus fault protection compared to standard RS-485 devices. Transceivers that operate in rugged industrial environments are often exposed to voltage transients greater than the -7 V to +12 V defined by the TIA/EIA-485A standard. To protect against such conditions, the generic RS-485 devices with lower absolute maximum ratings requires expensive external protection components. To simplify system design and reduce overall system cost, THVD24x2 devices are protected up to ±70 V without the need for any external components.

7.3.2 Integrated IEC ESD and EFT Protection

Internal ESD protection circuits protect the transceivers against electrostatic discharges (ESD) according to IEC 61000-4-2 of up to ±8 kV and against electrical fast transients (EFT) according to IEC 61000-4-4 of up to ±4 kV. Bus structures also protect against electrical fast transients (EFT) according to IEC 61000-4-4 for up to ±4 kV. With careful system design, integrated bus structures can enable EFT Criterion A at the system level (minimum to no data loss when transient noise is present).

7.3.3 Driver Overvoltage and Overcurrent Protection

The THVD24x2 drivers are protected against any DC supply shorts in the range of -70 V to +70 V. The devices internally limit the short circuit current to ± 250 mA to comply with the TIA/EIA-485A standard. In addition, a fold-back current limiting circuit reduces the driver short circuit current to less than ± 5 mA if the output fault voltage exceeds $|\pm 25$ V|.

If the junction temperature exceeds the T_{SHDN} threshold due to excessive power dissipation, the devices feature thermal shutdown protection that disables the driver and the receiver

7.3.4 Enhanced Receiver Noise Immunity

The differential receivers of THVD24x2 feature fully symmetric thresholds to maintain duty cycle of the signal even with small input amplitudes. In addition, 250 mV (typical) receiver hysteresis provides enhanced noise immunity. For THVD2412, typical 700 ns of glitch filter in receiver signal chain prevents high frequency noise pulses from the bus to appear on R pin.



7.3.5 Receiver Fail-Safe Operation

The receivers are fail-safe to invalid bus states caused by the following:

- · Open bus conditions, such as a disconnected connector
- · Shorted bus conditions, such as cable damage shorting the twisted-pair together
- Idle bus conditions that occur when no driver on the bus is actively driving

In any of these cases, the receiver outputs a fail-safe logic high state if the input amplitude stays for longer than $t_{D(OFS)}$ at less than $|V_{TH}|_{FSH}$.

7.3.6 Low-Power Shutdown Mode

Driving DE low and \overline{RE} high for longer than 500 ns puts the devices into the shutdown mode. If either DE goes high or \overline{RE} goes low, the counters reset. The devices does not enter the shutdown mode if the enable pins are in disable state for less than 50 ns. This feature prevents the devices from accidentally going into shutdown mode due to skew between DE and \overline{RE} .



7.4 Device Functional Modes

When the driver enable pin, DE, is logic high, the differential outputs Y and Z follow the logic states at data input D. A logic high at D causes Y to turn high and Z to turn low. In this case, the differential output voltage defined as $V_{OD} = V_Y - V_Z$ is positive. When D is low, the output states reverse: Z turns high, Y becomes low, and V_{OD} is negative.

When DE is low, both outputs turn high-impedance. In this condition, the logic state at D is irrelevant. The DE pin has an internal pull-down resistor to ground, thus when left open the driver is disabled (high-impedance) by default. The D pin has an internal pull-up resistor to V_{CC} , thus, when left open while the driver is enabled, output Y turns high and Z turns low.

INPUT	ENABLE	OUTI	PUTS	FUNCTION		
D	DE	Y	Z	FUNCTION		
Н	Н	Н	L	Actively drive bus high		
L	Н	L	Н	Actively drive bus low		
Х	L	Z	Z	Driver disabled		
Х	OPEN	Z	Z	Driver disabled by default		
OPEN	Н	Н	L	Actively drive bus high by default		

Table 7-1. Driver Function Table

When the receiver enable pin, \overline{RE} , is logic low, the receiver is enabled. When the differential input voltage defined as $V_{ID} = V_A - V_B$ is higher than the positive input threshold, V_{TH+} , the receiver output, R, turns high. When V_{ID} is lower than the negative input threshold, V_{TH-} , the receiver output, R, turns low. If V_{ID} is between V_{TH+} and V_{TH-} , the output is indeterminate.

When \overline{RE} is logic high or left open, the receiver output is high-impedance and the magnitude and polarity of V_{ID} are irrelevant. Internal biasing of the receiver inputs causes the output to go fail-safe high when the transceiver is disconnected from the bus (open-circuit), or the bus lines are shorted to one another (short-circuit), or the bus is not actively driven (idle bus).

	DIFFERENTIAL INPUT ENABLE OUTPUT												
		001101	FUNCTION										
$V_{ID} = V_A - V_B$	RE	R											
$V_{TH+} < V_{ID}$	L	Н	Receive valid bus high										
$V_{TH-} < V_{ID} < V_{TH+}$	L	?	Indeterminate bus state										
$V_{ID} < V_{TH-}$	L	L	Receive valid bus low										
X	Н	Z	Receiver disabled										
X	OPEN	Z	Receiver disabled by default										
Open-circuit bus	L	Н	Fail-safe high output										
Short-circuit bus	L	Н	Fail-safe high output										
Idle (terminated) bus	L	Н	Fail-safe high output										

Table 7-2. Receiver Function Table



8 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

8.1 Application Information

THVD2412 and THVD2442 are fault-protected, full-duplex RS-485 transceivers commonly used for asynchronous data transmissions. For these devices, the driver and receiver enable pins allow for the configuration of different operating modes.

8.2 Typical Application

An RS-485 bus consists of multiple transceivers connecting in parallel to a bus cable. To eliminate line reflections, each cable end is terminated with a termination resistor, R_T , whose value matches the characteristic impedance, Z_0 , of the cable. This method, known as parallel termination, generally allows for higher data rates over longer cable length.

Also note that a full-duplex RS-485 transceiver can be used as a half-duplex transceiver in an application by externally connecting driver output pins Y and Z to receiver input pins A and B respectively.





8.2.1 Design Requirements

RS-485 is a robust electrical standard suitable for long-distance networking that may be used in a wide range of applications with varying requirements, such as distance, data rate, and number of nodes.

8.2.1.1 Data Rate and Bus Length

There is an inverse relationship between data rate and cable length, which means the higher the data rate, the short the cable length; and conversely, the lower the data rate, the longer the cable length. While most RS-485 systems use data rates between 10 kbps and 100 kbps, some applications require data rates up to 250 kbps at distances of 4000 feet and longer. Longer distances are possible by allowing for small signal jitter of up to 5 or 10%.

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(1)



Figure 8-2. Cable Length vs Data Rate Characteristic

Even higher data rates are achievable (that is, 20 Mbps for the THVD2442) in cases where the interconnect is short enough (or has suitably low attenuation at signal frequencies) to not degrade the data.

8.2.1.2 Stub Length

When connecting a node to the bus, the distance between the transceiver inputs and the cable trunk, known as the stub, should be as short as possible. Stubs present a non-terminated piece of bus line which can introduce reflections of varying phase as the length of the stub increases. As a general guideline, the electrical length, or round-trip delay, of a stub should be less than one-tenth of the rise time of the driver, thus giving a maximum physical stub length as shown in Equation 1.

$$L_{(STUB)} \le 0.1 \times t_r \times v \times c$$

where

- t_r is the 10/90 rise time of the driver
- *c* is the speed of light $(3 \times 10^8 \text{ m/s})$
- *v* is the signal velocity of the cable or trace as a factor of *c*

8.2.1.3 Bus Loading

The RS-485 standard specifies that a compliant driver must be able to drive 32 unit loads (UL), where 1 unit load represents a load impedance of approximately 12 k Ω . Because the THVD24x2 devices consist of 1/8 UL transceivers which is approximately 96 k Ω input impedance, connecting up to 256 receivers to the bus is possible for a limited common mode range of - 7 V to 12 V.



8.2.1.4 Transient Protection

The bus pins of the THVD24x2 transceivers include on-chip ESD protection against \pm 16-kV HBM and \pm 8-kV IEC 61000-4-2 contact discharge. The International Electrotechnical Commission (IEC) ESD test is far more severe than the HBM ESD test. The 50% higher charge capacitance, $C_{(S)}$, and 78% lower discharge resistance, $R_{(D)}$, of the IEC model produce significantly higher discharge currents than the HBM model. As stated in the IEC 61000-4-2 standard, contact discharge is the preferred transient protection test method.



Figure 8-3. HBM and IEC ESD Models and Currents in Comparison (HBM Values in Parenthesis)

The on-chip implementation of IEC ESD protection significantly increases the robustness of equipment. Common discharge events occur because of human contact with connectors and cables. Designers may choose to implement protection against longer duration transients, typically referred to as surge transients.

EFTs are generally caused by relay-contact bounce or the interruption of inductive loads. Surge transients often result from lightning strikes (direct strike or an indirect strike which induce voltages and currents), or the switching of power systems, including load changes and short circuit switching. These transients are often encountered in industrial environments, such as factory automation and power-grid systems.

Figure 8-4 compares the pulse-power of the EFT and surge transients with the power caused by an IEC ESD transient. The left side of Figure 8-4 shows the relative pulse-power for a 0.5-kV surge transient and 4-kV EFT transient, both of which dwarf the 10-kV ESD transient visible in the lower-left corner. 500-V surge transients are representative of events that may occur in factory environments in industrial and process automation.

The right side of Figure 8-4 shows the pulse power of a 6-kV surge transient, relative to the same 0.5-kV surge transient. 6-kV surge transients are most likely to occur in power generation and power-grid systems.







For surge transients, high-energy content is characterized by long pulse duration and slow decaying pulse power. The electrical energy of a transient that is dumped into the internal protection cells of a transceiver is converted into thermal energy, which heats and destroys the protection cells, thus destroying the transceiver. Figure 8-5 shows the large differences in transient energies for single ESD, EFT, surge transients, and an EFT pulse train that is commonly applied during compliance testing.



Figure 8-5. Comparison of Transient Energies





8.2.2 Detailed Design Procedure

Figure 8-6 suggests a protection circuit against 1 kV surge (IEC 61000-4-5) transients. Table 8-1 shows the associated bill of materials. SMAJ30CA TVS diodes are rated to operate up to 30 V. This makes sure the protection diodes do not conduct if a direct RS-485 bus shorts to 24-V DC industrial power rail.



Figure 8-6. Transient Protection Against Surge Transients for Half-Duplex Devices

Table 8-1. Components List

DEVICE	FUNCTION	ORDER NUMBER	MANUFACTURER
XCVR	RS-485 transceiver	THVD2412 or THVD2442	TI
TVS	Bidirectional 400-W transient suppressor	SMAJ30CA	Littelfuse ⁽¹⁾

(1) See Third-Party Products



8.2.3 Application Curves



8.3 Power Supply Recommendations

For reliable operation at all data rates and supply voltages, V_{CC} supply can be decoupled with a 100nF ceramic capacitor located as close to the device supply pin as possible. This reduces supply voltage ripple present on the outputs of switched-mode power supplies, and compensates for the resistance and inductance of the PCB power planes.



8.4 Layout

8.4.1 Layout Guidelines

Robust and reliable bus node design often requires the use of external transient protection devices in order to protect against surge transients that may occur in industrial environments. Since these transients have a wide frequency bandwidth (from approximately 3MHz to 300MHz), high-frequency layout techniques should be applied during PCB design.

- 1. Place the protection circuitry close to the bus connector to prevent noise transients from propagating across the board.
- 2. Use V_{CC} and ground planes to provide low inductance. Note that high-frequency currents tend to follow the path of least impedance and not the path of least resistance.
- 3. Design the protection components into the direction of the signal path. Do not force the transient currents to divert from the signal path to reach the protection device.
- 4. Apply 100nF to 220nF decoupling capacitors as close as possible to the V_{CC} pins of transceiver, UART and/or controller ICs on the board.
- 5. Use at least two vias for V_{CC} and ground connections of decoupling capacitors and protection devices to minimize effective via inductance.
- 6. Use $1k\Omega$ to $10k\Omega$ pull-up and pull-down resistors for enable lines to limit noise currents in these lines during transient events.

8.4.2 Layout Example







9 Device and Documentation Support

9.1 Device Support

9.1.1 Third-Party Products Disclaimer

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To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

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9.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

9.6 Glossary

TI Glossary This glossary lists and explains terms, acronyms, and definitions.

10 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

С	hanges from Revision * (November 2023) to Revision A (March 2024)	Page
•	Revision A is the first public release of the datasheet	1

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
THVD2412DRCR	ACTIVE	VSON	DRC	10	5000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	2412	Samples
THVD2442DRCR	ACTIVE	VSON	DRC	10	5000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	2442	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

⁽⁶⁾ Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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PACKAGE OPTION ADDENDUM

29-Apr-2024



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TAPE AND REEL INFORMATION





QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal												
Device	-	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
THVD2412DRCR	VSON	DRC	10	5000	330.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2
THVD2442DRCR	VSON	DRC	10	5000	330.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2



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PACKAGE MATERIALS INFORMATION

29-Apr-2024



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
THVD2412DRCR	VSON	DRC	10	5000	367.0	367.0	35.0
THVD2442DRCR	VSON	DRC	10	5000	367.0	367.0	35.0

DRC 10

3 x 3, 0.5 mm pitch

GENERIC PACKAGE VIEW

VSON - 1 mm max height

PLASTIC SMALL OUTLINE - NO LEAD

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.





DRC0010J



PACKAGE OUTLINE

VSON - 1 mm max height

PLASTIC SMALL OUTLINE - NO LEAD



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M. 2. This drawing is subject to change without notice.

3. The package thermal pad must be soldered to the printed circuit board for optimal thermal and mechanical performance.



DRC0010J

EXAMPLE BOARD LAYOUT

VSON - 1 mm max height

PLASTIC SMALL OUTLINE - NO LEAD



NOTES: (continued)

 This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).

5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



DRC0010J

EXAMPLE STENCIL DESIGN

VSON - 1 mm max height

PLASTIC SMALL OUTLINE - NO LEAD



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



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